

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/720,411	BAER, RICHARD L.	
Examiner	Art Unit	
Alex Liew	2624	

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Class	Subclass	Date	Examiner
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Class	Subclass	Date	Examiner		
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SEARCH NO (INCLUDING SEARCH	TES I STRATEGY)
	DATE	EXMR
382/103,107 limited to text search	4/20/2007	AL
348 limited to text search	4/20/2007	AL
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